

P-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
- 40	0.010 at V _{GS} = - 10 V	- 16.1	33 nC			
- 40	0.014 at V _{GS} = - 4.5 V	- 13.3	33110			

FEATURES

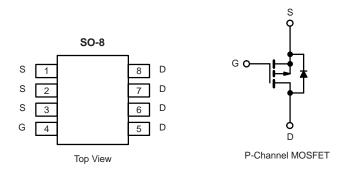
- Halogen-free According to IEC 61249-2-21 Definition
- 100 % R_g Tested
- 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC



COMPLIANT HALOGEN FREE



- Load Switch
- POL



ABSOLUTE MAXIMUM RATIN	IGS T _A = 25 °C,	unless other	erwise noted	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	- 40	V
Gate-Source Voltage		V_{GS}	± 20	v
	T _C = 25 °C		- 16.1	
Continuous Proin Current (T. – 150 °C)	T _C = 70 °C	1 .	- 12.9	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	- I _D	- 10.2 ^{b, c}	
	T _A = 70 °C		- 8.2 ^{b, c}	A
Pulsed Drain Current		I _{DM}	- 50	
Ocationas Ocama Basis Biodo Ocamad	T _C = 25 °C		- 5.3	
Continous Source-Drain Diode Current	T _A = 25 °C		- 2.1 ^{b, c}	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	- 28	
Single Pulse Avalanche Energy L = 0.1 mH		E _{AS}	39	mJ
	T _C = 25 °C		6.3	
Maximum Dowar Dissination	T _C = 70 °C		4	W
Maximum Power Dissipation	T _A = 25 °C	- P _D	2.5 ^{b, c}	VV
	T _A = 70 °C		1.6 ^{b, c}	
Operating Junction and Storage Temperatur	e Range	T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	37	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	16	20	C/VV		

Notes:

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 85 °C/W.



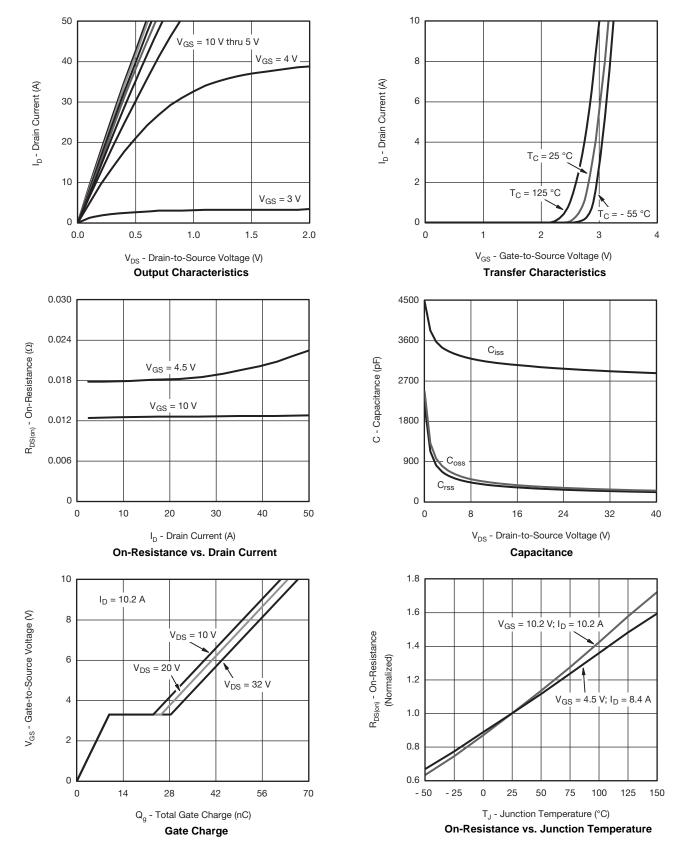
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static				•	I.	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 40			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 36		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = -250 \mu A$	- 1.2		- 2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zara Oata Valta va Basis Oarrast	I _{DSS}	V _{DS} = - 40 V, V _{GS} = 0 V			- 1	μА
Zero Gate Voltage Drain Current		V _{DS} = - 40 V, V _{GS} = 0 V, T _J = 55 °C			- 5	
On-State Drain Current ^a	I _{D(on)}	V _{DS} ≤ - 5 V, V _{GS} = - 10 V	- 25			Α
		V _{GS} = - 10 V, I _D = - 10.2 A		0.010		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 8.4 A		0.014		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 10.2 A		37		S
Dynamic ^b	L				I.	l
Input Capacitance	C _{iss}			3007		
Output Capacitance	C _{oss}	V _{DS} = - 20 V, V _{GS} = 0 V, f = 1 MHz		335		pF
Reverse Transfer Capacitance	C _{rss}			291		
Total Gate Charge		V _{DS} = - 20 V, V _{GS} = - 10 V, I _D = - 10.2 A		64	95	nC
	Q_g			33	50	
Gate-Source Charge	Q_{gs}	$V_{DS} = -20 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10.2 \text{ A}$		9.8		
Gate-Drain Charge	Q _{gd}			15.7		
Gate Resistance	R _g	f = 1 MHz	0.4	2	4	Ω
Turn-On Delay Time	t _{d(on)}			57	86	
Rise Time	t _r	$V_{DD} = -20 \text{ V}, R_{L} = 2.4 \Omega$		50	75	- -
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 8.2 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		40	60	
Fall Time	t _f			17	26	
Turn-On Delay Time	t _{d(on)}			13	20	ns
Rise Time	t _r	$V_{DD} = -20 \text{ V}, R_{L} = 2.4 \Omega$		11	20	- - -
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 8.2 A, V_{GEN} = - 10 V, R_g = 1 Ω		45	68	
Fall Time	t _f			9	18	
Drain-Source Body Diode Characteristi	cs			•	I.	,
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 5.3	_
Pulse Diode Forward Current	I _{SM}				- 50	A
Body Diode Voltage	V_{SD}	I _S = - 8.2 A, V _{GS} = 0 V		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t _{rr}			36	54	ns
Body Diode Reverse Recovery Charge Q _{rr}				41	62	nC
Reverse Recovery Fall Time	t _a	$I_F = -8.2 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °\text{C}$		20		1
Reverse Recovery Rise Time	t _b			16		ns

Notes:

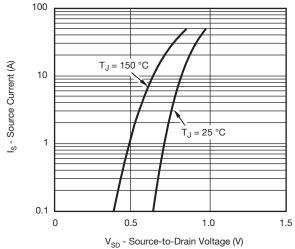
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

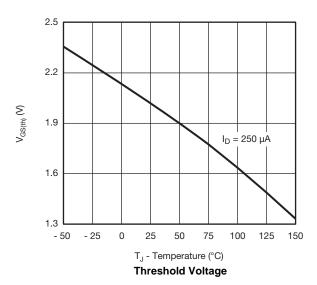






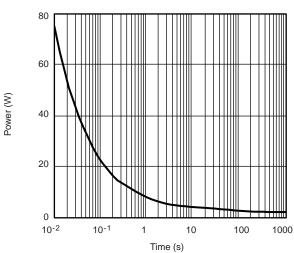




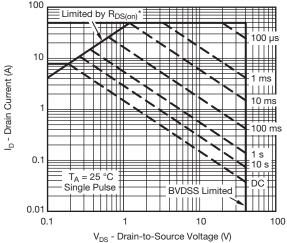


0.05 0.04 0.03 0.02 0.01 $T_{J} = 125 \, ^{\circ}\text{C}$ $T_{J} = 25 \, ^{\circ}\text{C}$ 0.01 V_{GS} - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



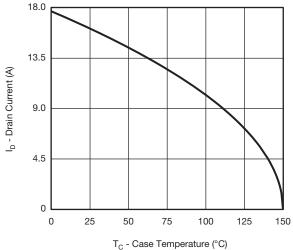
Single Pulse Power (Junction-to-Ambient)



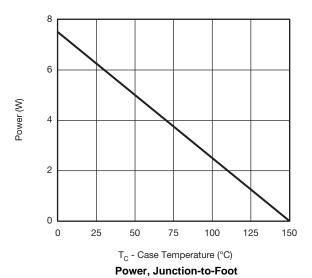
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

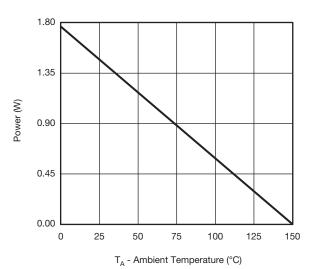
Safe Operating Area, Junction-to-Ambient





Current Derating*

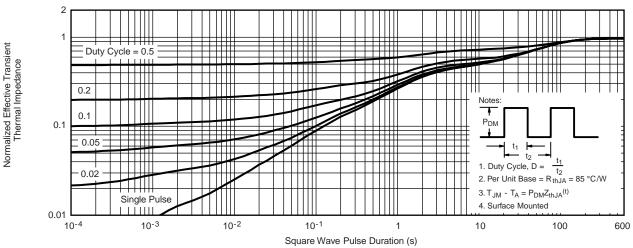




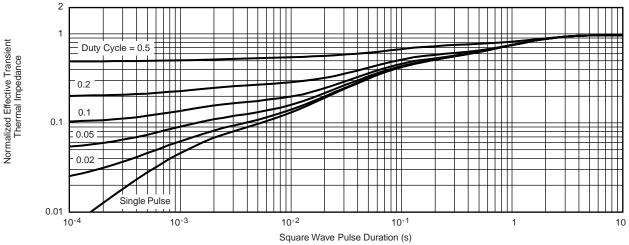
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





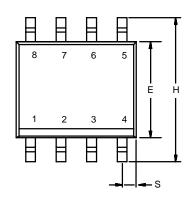
Normalized Thermal Transient Impedance, Junction-to-Ambient

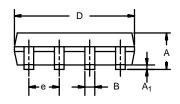


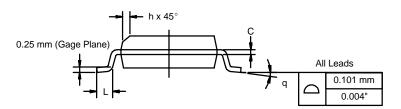
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012





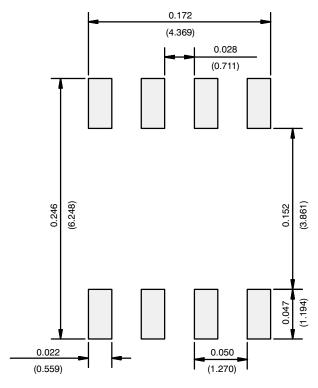


	MILLIN	IETERS	INC	INCHES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050	0.050 BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06						

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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